

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|---|---|------------------|---------|------------------|
| L20 | 3 | "6902681".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:34 |
| L21 | 0 | "10634001" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:34 |
| L22 | 1 | "10/634001" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:35 |
| L23 | 2821 | endpoint near detection | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:35 |
| L24 | 2 | "6258497".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:40 |
| L25 | 393 | (endpoint near detection).ti. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:41 |
| L26 | 2 | 25 and (gate near (dielectric and electrode)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:42 |
| L27 | 4 | 25 and (gate with (dielectric and electrode)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:42 |
| L28 | 5 | 25 and (gate same (dielectric and electrode)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:43 |

EAST Search History

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|-----|---------|--|---|----|----|------------------|
| L29 | 20 | 25 and (gate and (dielectric and electrode)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/08/21 16:43 |
| S1 | 462418 | plasma | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 07:30 |
| S2 | 199877 | etch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 10:47 |
| S3 | 17184 | S1 near S2 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 10:48 |
| S4 | 60405 | Chang.in. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 10:49 |
| S5 | 374 | S3 and S4 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 10:48 |
| S8 | 29319 | Chang adj et | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 10:49 |
| S9 | 1293 | S4 and S8 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 10:49 |
| S10 | 22 | S3 and S9 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 10:50 |
| S11 | 1026571 | silicon nitride | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 10:50 |

EAST Search History

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|-----|---------|------------------------------|---|----|----|------------------|
| S12 | 21 | S10 and S11 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 11:04 |
| S13 | 2 | "5,665,203".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 15:57 |
| S14 | 1437754 | LTO near silicon oxide | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 13:21 |
| S15 | 41 | LTO near (silicon adj oxide) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 14:04 |
| S16 | 1759114 | treatment | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 14:04 |
| S17 | 462418 | plasma | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 14:04 |
| S18 | 172453 | S17 and S16 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 14:05 |
| S19 | 24255 | S17 near S16 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 14:05 |
| S20 | 25 | ("5665203").URPN. | USPAT | OR | ON | 2005/08/29 14:16 |
| S21 | 8815 | S16 near S17 | USPAT | OR | ON | 2005/08/29 14:16 |
| S22 | 8815 | S17 near S16 | USPAT | OR | ON | 2005/08/29 14:17 |
| S23 | 282047 | bias | USPAT | OR | ON | 2005/08/29 14:20 |
| S24 | 289707 | S22 nead S23 | USPAT | OR | ON | 2005/08/29 14:17 |
| S25 | 2991911 | zero or no | USPAT | OR | ON | 2005/08/29 14:17 |
| S26 | 2 | S22 near S23 | USPAT | OR | ON | 2005/08/29 15:33 |

EAST Search History

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|-----|--------|----------------------------------|---|----|----|------------------|
| S27 | 125166 | RF | USPAT | OR | ON | 2005/08/29 14:20 |
| S28 | 62 | S22 near S27 | USPAT | OR | ON | 2005/08/29 14:22 |
| S29 | 8432 | plasma near etch | USPAT | OR | ON | 2005/08/29 14:22 |
| S30 | 3 | S28 and S29 | USPAT | OR | ON | 2005/08/29 14:23 |
| S31 | 3669 | reduce near (charge or charging) | USPAT | OR | ON | 2005/08/29 14:23 |
| S32 | 571 | S31 and S17 | USPAT | OR | ON | 2005/08/29 14:23 |
| S33 | 222 | S32 and S23 | USPAT | OR | ON | 2005/08/29 14:24 |
| S34 | 106 | S33 and S27 | USPAT | OR | ON | 2005/08/29 14:24 |
| S35 | 547792 | inert or ambient | USPAT | OR | ON | 2005/08/29 14:24 |
| S36 | 58 | S34 and S35 | USPAT | OR | ON | 2005/08/29 14:29 |
| S37 | 12 | S36 and S29 | USPAT | OR | ON | 2005/08/29 14:29 |
| S38 | 20853 | PMOS | USPAT | OR | ON | 2005/08/29 15:33 |
| S39 | 0 | "6656832.pn" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 15:58 |
| S40 | 2 | "6656832".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 15:59 |
| S41 | 436442 | high adj frequency | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:00 |
| S42 | 211441 | MHz | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:00 |
| S43 | 689 | S41 near S41 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:00 |
| S44 | 11 | zero near (RF adj bias) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:15 |

EAST Search History

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|-----|------|--|---|----|----|------------------|
| S45 | 0 | S44 and S43 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:00 |
| S46 | 1 | 09/775664 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:08 |
| S47 | 8 | inductively adj coupled near plasma near etch.ab. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:16 |
| S48 | 0 | inductively adj coupled near etch. ab. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:17 |
| S49 | 866 | inductively adj coupled and etch.ab. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:17 |
| S50 | 328 | S49 and RIE | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:17 |
| S51 | 208 | S50 and bias | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:17 |
| S52 | 172 | S51 and RF | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:17 |
| S53 | 107 | S52 and MHZ | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:29 |
| S54 | 2305 | (no or zero) near bis | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:29 |

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|-----|---------|--|---|----|----|------------------|
| S55 | 0 | S53 and S54 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:30 |
| S56 | 2641 | overetch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:30 |
| S57 | 3993 | no near bias | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:30 |
| S58 | 35 | S56 and S57 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/08/29 16:40 |
| S59 | 2127396 | substrate | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:32 |
| S60 | 1621 | (gate adj dielectric) near (((silicon adj dioxide) or (SiO2 or SiOx or SiOn or "SiO.sub2" or "SiO.subx" or "SiO.subn" or "SiO.sub.2" or "SiO.sub.x" or "SiO.sub.n")) or (high near (constant or k))) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:34 |
| S62 | 21352 | polysilicon near gate | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:51 |
| S63 | 981 | (hard adj mask) near (((silicon adj dioxide) or (SiO2 or SiOx or SiOn or "SiO.sub2" or "SiO.subx" or "SiO.subn" or "SiO.sub.2" or "SiO.sub.x" or "SiO.sub.n")) or ((silicon adj nitride) or (SiN4 or SiNn or "SiN.sub4" or "SiN.subx" or "SiN.subn" or "SiN.sub.4" or "SiN.sub.x" or "SiN.sub.n")) or (SiO3N4 or "Si.O. sub. 3N.sub.4" or "Si.O.sub.xN.sub.x" or "Si.O.sub.nN.sub.n" or "Si.O.sub.xN.sub.n" or "Si.O.sub.nN.sub.x")) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:51 |

EAST Search History

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|-----|-------|-----------------------------|---|----|----|------------------|
| S64 | 655 | S59 and S60 and S62 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:39 |
| S66 | 1 | 10/634001 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:18 |
| S67 | 12 | S64 and S63 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:44 |
| S68 | 13773 | (hard adj mask) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:51 |
| S69 | 101 | S60 and S62 and S68 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:51 |
| S70 | 712 | (polysilicon near gate).ti. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:57 |
| S71 | 2 | S69 and S70 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 07:52 |
| S74 | 3569 | polysilicon near etch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:18 |
| S76 | 135 | bulk adj etch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:19 |
| S77 | 4390 | over adj etch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:19 |

EAST Search History

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|-----|-------|---|---|----|----|------------------|
| S78 | 10 | S74 and S76 and S77 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:24 |
| S79 | 0 | S78 and bias | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:24 |
| S80 | 876 | S74 and bias | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:24 |
| S81 | 793 | S80 and source | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:25 |
| S82 | 0 | S81 and S76 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 15:17 |
| S83 | 32 | S81 and ((polysilicon near etch).ab.) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:35 |
| S84 | 52215 | lower near power | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:35 |
| S85 | 2188 | expose near gate | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:40 |
| S86 | 66 | S84 and S85 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:35 |
| S87 | 74 | expose near gate near dielectric | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:40 |

EAST Search History

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|-----|----|---|---|----|----|------------------|
| S88 | 4 | S84 and S87 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:41 |
| S89 | 1 | "3" near step near polysilicon near etch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:42 |
| S90 | 2 | "4" near step near polysilicon near etch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 08:52 |
| S91 | 2 | "5242536".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 09:05 |
| S92 | 7 | AMAT and Cl2 and HBr | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 09:05 |
| S93 | 6 | AMAT and Cl2 and HBr and polysilicon | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 09:07 |
| S94 | 6 | AMAT and Cl2 and HBr and (polysilicon adj etch) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 09:07 |
| S95 | 28 | AMAT and (polysilicon adj etch) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 09:29 |
| S98 | 1 | plasma near treat near gate near dielectric | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 09:33 |
| S99 | 2 | "5273920".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 09:44 |

EAST Search History

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|----------|------|---|---|----|----|------------------|
| S10 0 | 3 | "6902681".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 10:31 |
| S10 1 | 2 | "6479403".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 10:32 |
| S10 2 | 2 | "6579809".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 12:26 |
| S10 3 | 0 | polysilicon near overetch near zero near bias | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 13:11 |
| S10 4 | 0 | polysilicon and (overetch near zero near bias) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 13:11 |
| S10 5 | 17 | polysilicon and overetch and (zero near bias) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 13:16 |
| S10 6 | 1 | polysilicon and overetch and (zero near rf) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 13:17 |
| S10 7 | 1 | overetch and (zero near rf) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 13:17 |
| S10 8 | 7 | (zero near rf near bias) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 15:16 |
| S10 9 | 6708 | (source and bias) near power | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 15:17 |

EAST Search History

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|----------|------|-------------------------------------|---|----|----|------------------|
| S11 0 | 3569 | polysilicon near etch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 15:17 |
| S11 1 | 177 | S109 and S110 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 15:17 |
| S11 2 | 4 | S111 and HBr and Cl2 and O2 and CF4 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 15:22 |
| S11 3 | 2 | 09/875069 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 15:23 |
| S11 4 | 2 | S112 and S113 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/08 15:23 |
| S11 5 | 2 | "6,284,665".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 07:40 |
| S11 6 | 2 | "6,656,832".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 07:41 |
| S11 7 | 1 | 10/634001 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 07:42 |
| S11 8 | 1 | 10/791756 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 14:15 |
| S11 9 | 1 | 10/752,362 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 14:51 |

EAST Search History

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|----------|---------|------------------------------|---|----|----|------------------|
| S12 0 | 1 | 10/277261 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:03 |
| S12 1 | 2 | "5665203".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:04 |
| S12 2 | 2 | "6284665".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:07 |
| S12 3 | 22 | about near "13.56MHz" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:07 |
| S12 4 | 1063 | about near ("13.56" adj MHz) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:08 |
| S12 5 | 728 | etching and plasma and S124 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:09 |
| S12 6 | 90847 | GaAs | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:13 |
| S12 7 | 24 | S125 and S126 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:10 |
| S12 8 | 1135477 | (self near bias) or puls\$2 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:10 |
| S12 9 | 14 | S127 and S128 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:10 |

EAST Search History

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|----------|--------|--|---|----|----|------------------|
| S13 0 | 5 | S129 and pulse | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:10 |
| S13 1 | 91089 | GaAs or (gallium adj arsenide) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:14 |
| S13 2 | 118987 | GaAs or (gallium adj arsenide) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:14 |
| S13 3 | 19016 | S132 and etch | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:14 |
| S13 4 | 9155 | S133 and plasma | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:14 |
| S13 5 | 0 | S134 and inductiver | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:14 |
| S13 6 | 460 | S134 and inductive | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:14 |
| S13 7 | 114 | (S136 and (pulse or pulsed)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:18 |
| S13 8 | 6 | S137 and (about near ("13.56" adj MHZ)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:18 |
| S13 9 | 600 | etch near S132 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:17 |

EAST Search History

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|----------|-------|--|---|----|----|------------------|
| S14 0 | 235 | S139 and plasma | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:17 |
| S14 1 | 107 | S140 and rf | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:17 |
| S14 3 | 15 | (S141 and (pulse or pulsed)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:21 |
| S14 4 | 8 | high near frequency near pulsed near plasma | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 15:36 |
| S14 5 | 54992 | cmp | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 16:41 |
| S14 6 | 1208 | bulk near removal | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 16:42 |
| S14 7 | 573 | selective near polishing | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 16:41 |
| S14 8 | 155 | bulk near polishing | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 16:42 |
| S14 9 | 3 | S147 and S148 and S145 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 16:48 |
| S15 0 | 2 | "11023862" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 16:44 |

EAST Search History

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|----------|-----|------------------------|---|----|----|------------------|
| S15 1 | 0 | 11/023862 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 16:46 |
| S15 2 | 149 | two near step near cmp | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 16:46 |
| S15 3 | 2 | "6293845".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 18:11 |
| S15 4 | 2 | "20040055993" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/03/09 18:12 |